



# 认证证书

兹证明

## 安徽捷方电子有限公司

中国安徽省宣城市广德经济开发区科技创业园 2#标准化厂房 1层南侧& 2层 &3层 242200

经 NSF-ISR 评估，已建立的质量管理体系符合如下标准：

### IATF 16949:2016

认证范围：  
电路板的生产

删减： 产品设计



IATF 证书编号：	0447224
证书编号：	CNIATF053013
证书颁发日期：	2022/03/30
注册日期：	2022/03/26
到期日期*：	2025/03/25

Jennifer Morecraft,  
Global Managing Director

### NSF International Strategic Registrations

789 North Dixboro Road, Ann Arbor, Michigan 48105 | (888) NSF-9000 | [www.nsf-isr.org](http://www.nsf-isr.org)

Authorized Registration and /or Accreditation Marks. This certificate is property of NSF-ISR and must be returned upon request.

\*Company is audited for conformance at regular intervals. To verify registrations call (888) NSF-9000 or visit our web site at [www.nsf-isr.org](http://www.nsf-isr.org)



# *Certificate of Registration*

This certifies that the Quality Management System of

## **Anhui Jiefang Electronics Co., Ltd**

South side of 1st floor,2nd floor,3rd floor,No.2 standardized workshop, Science and Technology Innovation Park, Guangde Economic Development Zone, Xuancheng City, Anhui Province,China242200

Has been assessed by NSF-ISR and found to be in conformance to the following standards(s):

### **IATF 16949:2016**

#### **Scope of Registration:**

Manufacturing of Printed Circuit Board Assembly

#### **Exclusions:** Product Design



IATF Certificate Number:	0447224
Certificate Number:	CNIATF053013
Certificate Issue Date:	30-MAR-2022
Registration Date:	26-MAR-2022
Expiration Date*:	25-MAR-2025

A handwritten signature in black ink, reading "Jennifer Morecraft".

Jennifer Morecraft,  
Global Managing Director

### **NSF International Strategic Registrations**

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